

第五届原子光谱及相关技术学术会议

高性能ICPOES及其应用

- 高光眸
- 2018-9-21



40
YEARS OF
MAKING
LIFE BETTER
IN CHINA

ARE YOU
IN?



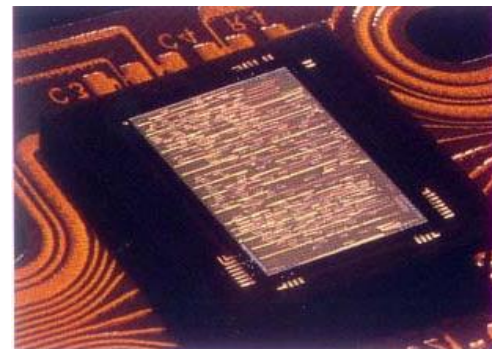
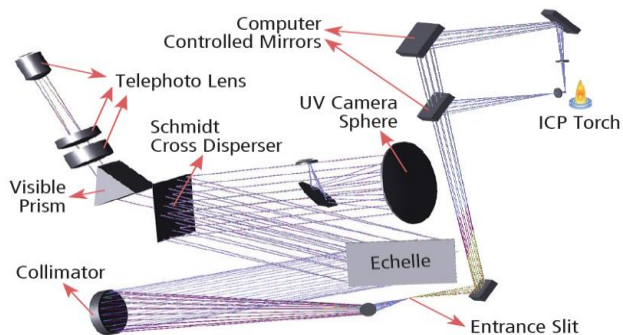
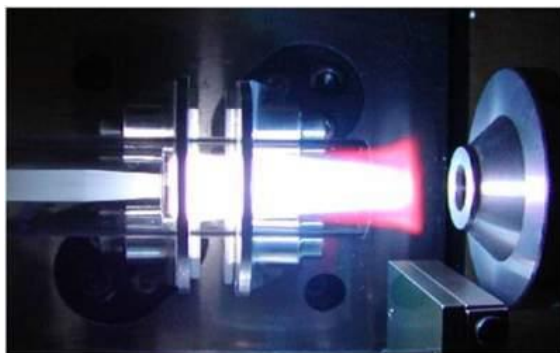
ICPOES的发展过程

- 1961年Reed设计了在大气压下稳定的高频震荡放电（ICP）
- 1964年S.Greefield发表第一篇ICPOES应用报告
- 1975年第一台商用ICPOES（垂直火炬多通道）
- 1977年第一台单道扫描性ICPOES
- 1982年单道+多通道ICPOES
- 1990年第一台水平火炬ICPOES
- 1991年第一台全谱直读型ICPOES
- 1994年第一台双向观测ICPOES
- 2011年第一台平板等离子体ICPOES
- 2013年第一台垂直火炬双向观测ICPOES



ICPOES硬件的变迁

功能模块	发展变化
ICP的布局及观测方式	垂直火炬径向观测→ 水平火炬轴向观测 →水平火炬双向观测→垂直火炬双向观测
射频发生器	电子管放大型→固态放大型→ 变频固态放大型
分光系统	凹面光栅多道同时型→平面光栅单道扫描型→ 中阶梯光栅二维色散全谱直读型
检测器	光电倍增管（PMT）→ 固态检测器（CCD、CID）



ICPOES性能的改进之一（检测限）

表1 各元素 ICP-AES分析法的检测限(L. D., µg/L)

Table 1 The detection limit for elements by ICP-AES(L. D., µg/L)

分析元素	Ag	Al	As	Au	B	Ba	Be	Bi	Ca	Cd	Ce	Co	Cr	Cu	Dy	Er	Eu
L. D. 80 ^{*1}	6.6	22	50	16	4.5	1.2	0.25	21	0.18	2.4	50	5.0	4.0	2.3	10	9.4	2.5
L. D. 99 ^{*2}	0.2	0.2	0.9	0.6	0.3	0.04	0.05	2.6	0.02	0.09	2.0	0.2	0.2	0.2	1.0	0.7	0.2
分析元素	Fe	Ga	Gd	Ge	HI	Hg	Ho	In	Ir	K	La	Li	Lu	Mg	Mn	Mo	Na
L. D. - 80 ^{*1}	1.7	21	14	17	11	25	5.4	59	25	60	9.4	1.8	0.94	0.14	1.3	7.4	29
L. D. - 99 ^{*2}	0.2	4	0.9	6.0	3.3	0.5	0.4	9	5	0.2	1	0.2	0.2	0.01	0.04	0.2	0.5
分析元素	Nb	Nd	Ni	Os	P	Pb	Pd	Pr	Pt	Re	Rh	Ru	S	Sb	Sc	Se	Si
L. D. - 80 ^{*1}	39	47	9.4	0.34	73	40	40	36	28	57	40	28	-	17	-	70	9
L. D. - 99 ^{*2}	5	2	0.3	0.13	1.5	1.5	3	2	4.7	3.3	5	6	9	2.0	0.09	1.5	1.5
分析元素	Sm	Sn	Sr	Ta	Tb	Te	Th	Ti	Tl	Tm	U	V	W	Y	Yb	Zn	Zr
L. D. - 80 ^{*1}	40	25	0.4	24	22	39	61	3.5	39	4.9	240	4.6	28	3.2	1.7	1.7	6.6
L. D. - 99 ^{*2}	2	1.3	0.01	5.3	2	10	5.4	0.05	1.0	0.6	15	0.2	2.0	0.3	0.3	0.2	0.3

*1 为 20 世纪 80 年代文献上所发表的数据。引自文献^[2]；

*2为 20 世纪 90 年代末商品仪器的最好水平。引自各仪器制造公司所提供的技术资料。

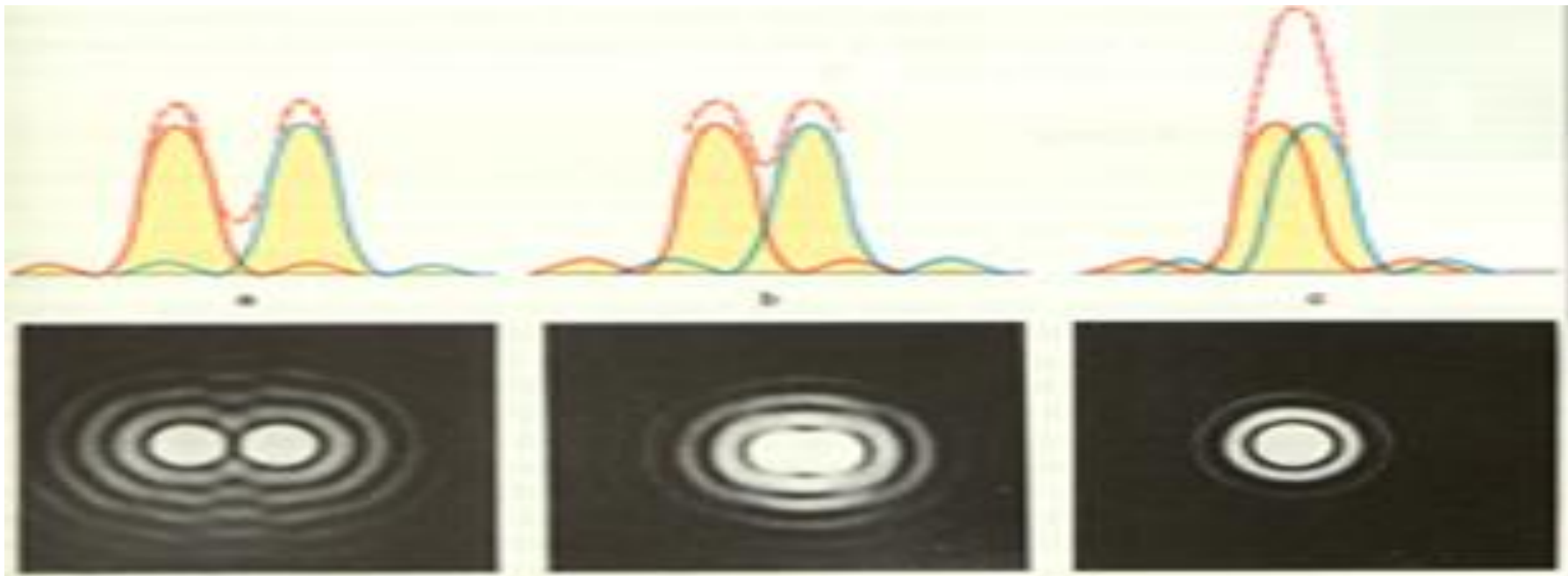
ICPOES性能的改进之二（光学分辨率）

0.006nm的光学分辨率可区分相差0.015nm的干扰线。如P213.617nm和Cu213.598nm

0.005-0.006nm

0.007-0.008nm

0.009-0.010nm



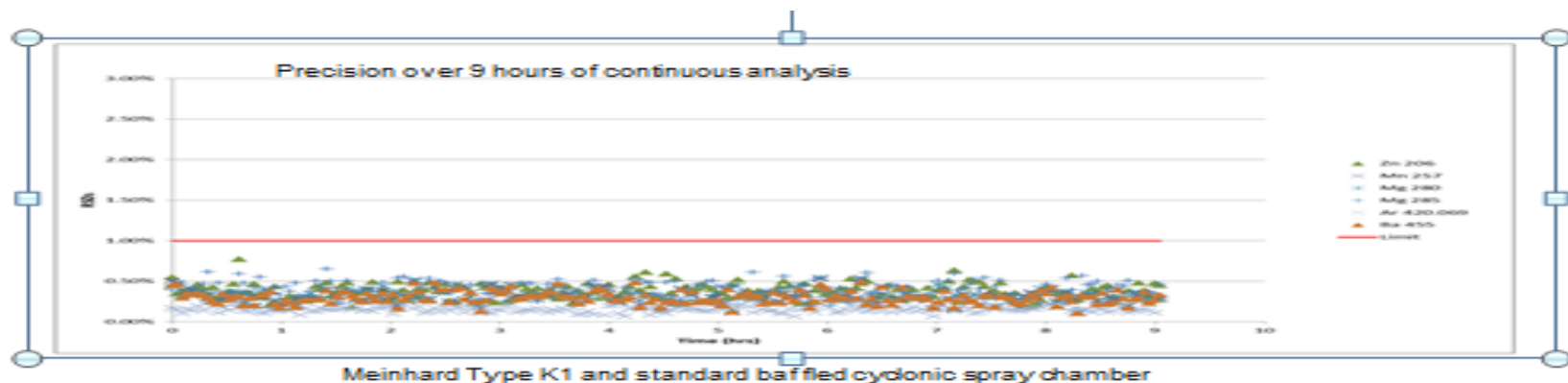
ICPOES性能的改进之二（光学分辨率）

- 计算举例：**ICP5110**
- 光栅刻线94.74条/mm，计算得 $d=1\text{mm}/94.74=0.01056\text{mm}$
- 闪耀角 44.77° ，计算得 $\cos(\beta)=0.714$
- 当 $\lambda=200\text{nm}$ 时，光学级数74级，
- 根据光栅方程 $m*\lambda=d*(\sin\alpha+\sin\beta)$ ，光栅的角色散率公式 $d\beta/d\lambda=m/(d*\cos\beta)$
- 角色散率 $=m/(d*\cos\beta)=74/(0.01056*0.714)=9814.5\text{弧度/mm}=0.0098\text{弧度/nm}$
- 焦距为400毫米、像素宽度0.0125mm，
- 线色散率倒数 $=1/(\text{角色散率}*\text{焦距})=1/(0.00098*400)=0.255\text{nm/mm}$
- 仪器在200nm像素分辨率为：
- 像素分辨率 $=\text{线色散率倒数}*\text{像素宽度}=0.255*0.0125=0.0032\text{nm}$

- **ICP5110在200nm处光学分辨率 $=2*\text{像素分辨率}=0.0032*2=0.0064\text{nm}$**

ICPOES的性能改进之三（稳定性）

(1) 高频发生器的改进: 由于 ICP 的电子密度和激发温度随频率的增加而减低, 而光源的背景强度 (Ar 的连续光谱) 则与频率的平方成反比, 随频率的提高要降低得多^[6]。经比较^[7]发现, 采用 40.68MHz 的高频发生器, 有较高的信背比 (S/B), 与 27.12MHz 发生器相比信背比有显著提高, 检出限改善可达 4 倍。为了提高高频发生器的稳定性, 采用具有很高的频率稳定性 (优于 1 KHz) 和输出功率稳定性 ($\leq 0.1\%$) 的固态发生器, 等离子体阻抗可自动调节补偿, 并由计算机控制工作参数, 设定点火程序, 可自动点火。因此, 新型的商品仪器均已使用 40.68MHz 固态发生器, 结合对样品的引入系统采取恒温, 提高进样的稳定性, 加上光学系统的恒温, 热稳定性高 ($\pm 0.1^\circ\text{C}$), 使仪器预热时间大为缩短, 开机 10min 即可达到稳定, 使仪器的短时间稳定性可提高到 0.3 %RSD, 长时间稳定性达 $< 1\%$ RSD。大大提高了 ICP-AES 法的分析精度和准确性。



9-hour stability run results in $< 1\%$ RSD

主流（好的）ICPOES的基本要求

- ▶ 高灵敏度（检出限0.1-1ppb）
- ▶ 高分辨率（200nm处优于0.007nm）
- ▶ 高稳定性（短期Rsd%优于0.5%）

好的光谱

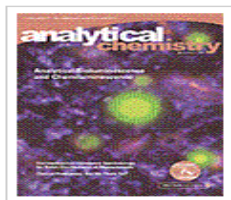
耐各种复杂基体样品 →

好的ICP

好的ICP光谱



实际样品测定对ICPOES的要求之一（氧化硼中Be测定）



期刊文献 Certification of Beryllium Mass Fraction in SRM 1877 Beryllium Oxide Powder Using High-Performance Inductively Coupled Plasma Optical Emission Spectrometry with Exact Matching

作者: [Winchester, Michael R. mrw@nist.gov](mailto:mrw@nist.gov) [Turk, Gregory C.](#) [Butler, Therese A.](#) [Oatts, Thomas J.](#) [Coleman, Charles](#) [Nadratowski, Donald](#) [Sud, Ritu](#) [Hoover, Mark D.](#) [Stefaniak, Aleksandr B.](#)

High-performance inductively coupled plasma optical emission spectrometry (HP-ICP-OES) was used to certify the Be mass fraction in National Institute of Standards and Technology (NIST) Standard Reference Material (SRM) 1877 Beryllium Oxide Powder. The certified value and expanded uncertainty expressed at a 95% confidence level is **(0.3576 ± 0.0024) g/g.**

- 二倍标准偏差0.6%，ICPOES短期RSD%必须低于0.3%

实际样品测定对ICPOES的要求之二（贵金属定值）

- **The Customer Request**

- Demonstrate that the Optima is capable of analyzing high accurate and precise determinations of PMGs

- **The Elements**

- Au, Pt, Pd, Rh, Ir, Ag, Ru
- e.g. **ISO 11494 & 11495**

- **The Problem**

- Analytical Precision Relatively Poor : 0.20 - 0.40%

$$\bar{m}_{Pt,fin} = \frac{1}{5} \left(\sum_{n=1}^5 m_{Pt} \right)$$

The RSD of m_{Pt} shall not exceed 0.30 %.

INTERNATIONAL
STANDARD

ISO
11494

Second edition
2014-12-01

Jewellery — Determination of
platinum in platinum jewellery alloys
— ICP-OES method using yttrium as
internal standard element

*Joaillerie, bijouterie — Dosage du platine dans les alliages de platine
pour la joaillerie, bijouterie — Méthode par ICP-OES utilisant
l'yttrium comme étalon interne*

实际样品测定对ICPOES的要求之三（磷肥测定）

4.3.5 分析结果的表述

有效五氧化二磷(P_2O_5)含量 w_1 以质量分数(%)表示,按式(1)计算:

$$w_1 = \frac{(m_1 - m_2) \times 0.03207}{m_{01} \times \frac{V_{01}}{250}} \times 100$$
$$= \frac{(m_1 - m_2) \times 801.75}{m_{01} V_{01}} \dots\dots\dots(1)$$

式中:

m_1 ——测定时所得磷钼酸喹啉沉淀质量,单位为克(g);

m_2 ——空白试验时,所得磷钼酸喹啉沉淀质量,单位为克(g);

0.03207——磷钼酸喹啉质量换算为五氧化二磷质量的系数;

m_{01} ——试料的质量,单位为克(g);

V_{01} ——所取试样溶液的体积,单位为毫升(mL);

250——试样溶液总体积,单位为毫升(mL)。

取平行测定结果的算术平均值为测定结果。

4.3.6 允许差

平行测定结果的绝对差值不大于0.20%。

不同实验室测定结果的绝对差值不大于0.30%。



实际样品测定对ICPOES的要求之四（标准溶液）

- NIST produces and certifies 70 Spectrometric Solution SRMs
 - 1000's sold annually for calibration of ICP, AAS
 - typically 10 mg/g
 - **~0.3% uncertainty**
- transfer standards used for calibration



高性能ICPOES要求具备高稳定性 (RSD% \leq 0.1%)

- 化学分析的精度 (RSD% $<$ 0.2%)，仪器分析的便捷

Anal. Chem. 2001, 73, 4821–4829

Single-Element Solution Comparisons with a High-Performance Inductively Coupled Plasma Optical Emission Spectrometric Method

Marc L. Salit,* Gregory C. Turk, Abigail P. Lindstrom, Therese A. Butler, Charles M. Beck II, and Bruce Norman

Chemical Science and Technology Laboratory, National Institute of Standards and Technology, 100 Bureau Drive, Gaithersburg, Maryland 20899-8391

A solution-based inductively coupled plasma optical emission spectrometric (ICP-OES) method is described for elemental analysis with relative expanded uncertainties on the order of 0.1% relative. The single-element determinations of 64 different elements are presented, with aggregate performance results for the method and parameters for the determination of each element. The performance observed is superior to that previously reported for ICP-OES, resulting from a suite of technical strategies that exploit the strengths of contemporary spectrometers, address measurement and sample handling noise sources, and permit rugged operation with small uncertainty. Taken together, these strategies constitute high-performance ICP-OES.

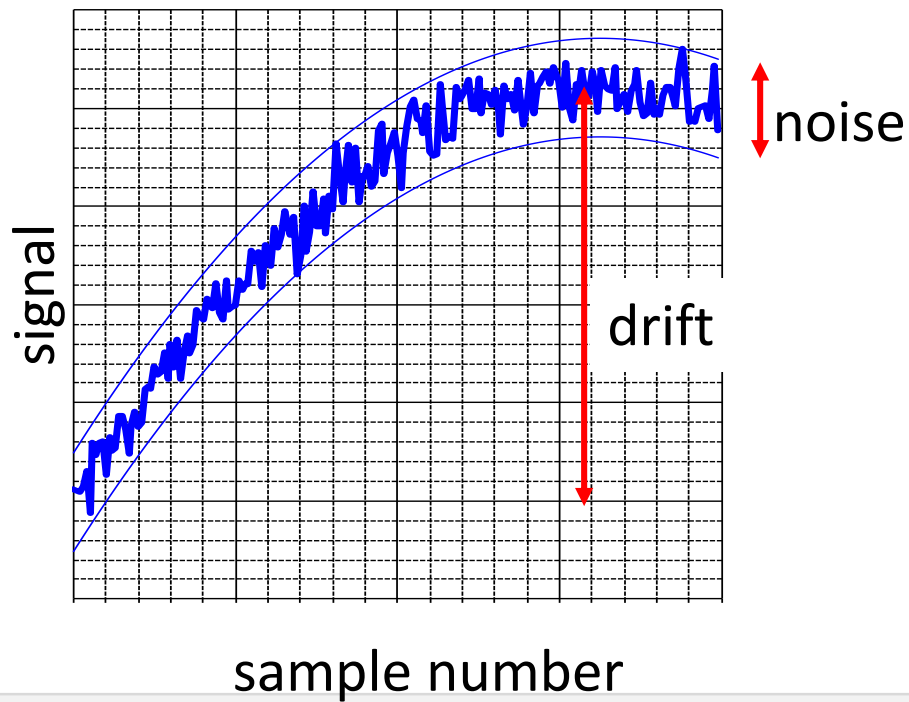
quantitatively different from that previously reported for ICP-OES results. Different chemical information becomes available with this ability to discriminate between solutions of very similar composition—an improvement in concentration resolution. Additionally, at this level of uncertainty, uncertainty is dominated by effects other than spectroscopic measurement (e.g., sample handling and preparation).

Measurements are performed using unmodified commercially available equipment and are significantly less costly than classical analysis. The opportunity to achieve results of the quality expected of classical analysis with instrumental efficiency enables new analytical applications. In contrast to classical analysis, instrumental automation permits the analysis of multiple samples with little incremental cost per sample. Similar to classical analysis, this method is suitable for determination of “major” and “minor”

信号波动=噪音+漂移

- 噪声是短期的
- 漂移是长期的

Drift is major
source of
uncertainty



Drift Correction

$$S_{measured} = S_{truth} + \epsilon_{drift} + \epsilon_{noise}$$

- separate variables to estimate drift as $f(t)$
 - use grand mean for sample to estimate S_{truth}
 - create time series of deviations from mean
 - use **ALL** standards and samples
 - this is our estimate of $(\epsilon_{drift} + \epsilon_{noise})!$
 - use relative deviations for multiplicative drift, absolute deviations for additive drift
 - fit smooth function to these deviations
 - this is our estimate of $\epsilon_{drift}!$

内标校正对于漂移效果明显：从10% → 0.5%

Spectrochimica Acta, Vol. 38B, No. 9, pp. 1227-1253, 1983.
Printed in Great Britain.

0584-8547/83 \$3.00 + .00
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Improved performance using internal standardization in inductively-coupled plasma emission spectroscopy

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Perkin-Elmer Corporation, Main Avenue, Norwalk, CT 06856, U.S.A.

(Received 30 June 1982, in revised form 25 February 1983)

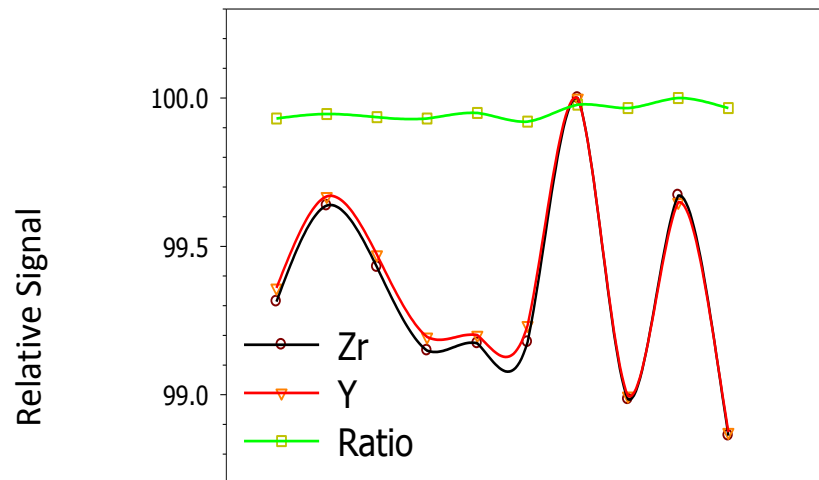
Abstract—Significantly improved performance in ICP emission spectroscopy is possible using internal standardization given the proper choice of operating conditions. A dual monochromator detection system was used to study the correlation between two emission signals recorded simultaneously as several ICP parameters were varied. The behavior of the signal formed by dividing the analyte and reference signals was also measured.

The noise behavior of twenty analytically important elements was compared to that of a manganese ion line used as the internal standard for a single, compromise choice of ICP operating parameters (RF power = 1250 W, carrier gas flow rate = 0.7 or 0.9 l/min, and viewing height = 20 mm). The elements differed widely in excitation and ionization energies. Sample concentrations were chosen so that the analyte emission signals were sufficiently intense that the noise and drift contributions due to plasma background and shot noise could be ignored. Under these conditions very good signal correlation ($r \geq 0.95$) and similar noise proportionality factors were observed leading to noise reductions of $\geq 10 \times$ after signal division in almost every instance. After signal division the noise, defined as the relative standard deviation of the emission signal, (time constant = 1.0 s, $n = 20$) was less than 0.1%. The closely similar noise behavior is attributed to sample density fluctuations arising from corresponding fluctuations of the sample aerosol density. Good correlation is also observed between fluctuations in the plasma background simultaneously detected at two widely separated wavelengths when appropriate steps are taken to reduce shot noise.

At carrier gas flow rates above 1.0 l/min and at viewing heights below 15 mm or above 20 mm, the signal correlation is reduced or absent, yielding little or no improvement using internal standardization.

The use of internal standardization leads to other improvements in analytical performance in addition to noise reduction. Drift is reduced, and nebulizer performance is improved in that it is less sensitive to variations in liquid sample uptake rate, or nebulizer instabilities associated with high solids content sample introduction. The divided signal takes much less time to reach equilibrium following introduction of a new sample.

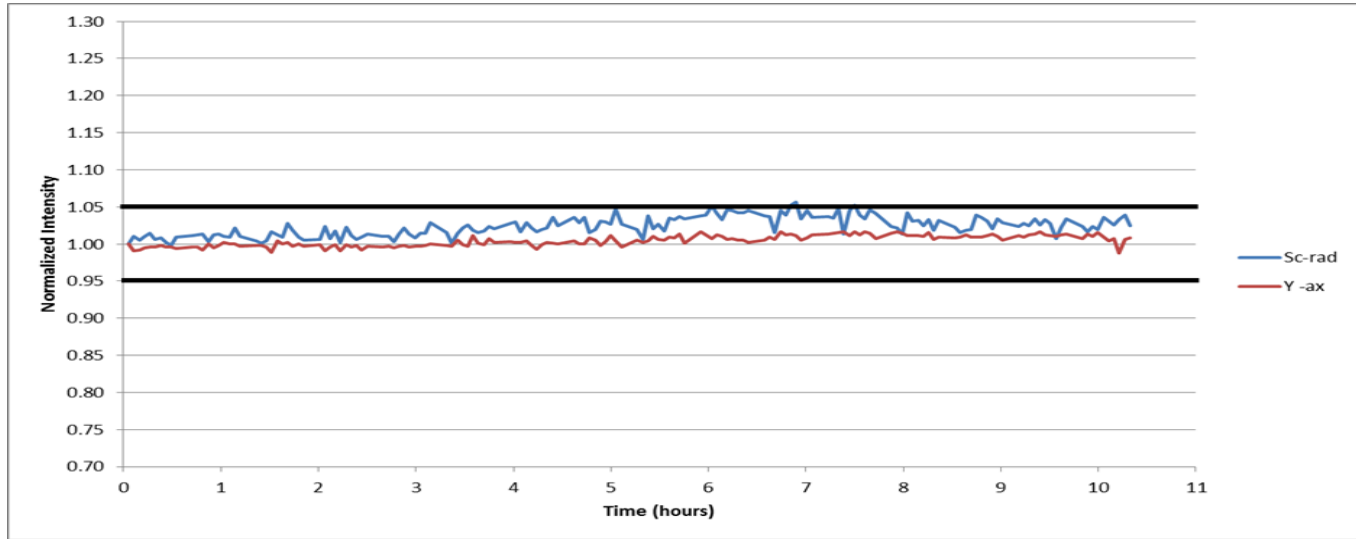
- precision enhancement
 - matched internal standard
 - can be ~20x improvement



Establishing Traceability to NIST SRMs
with High Performance ICP-OES
Marc Salit, NIST and Sue Evans, VHG

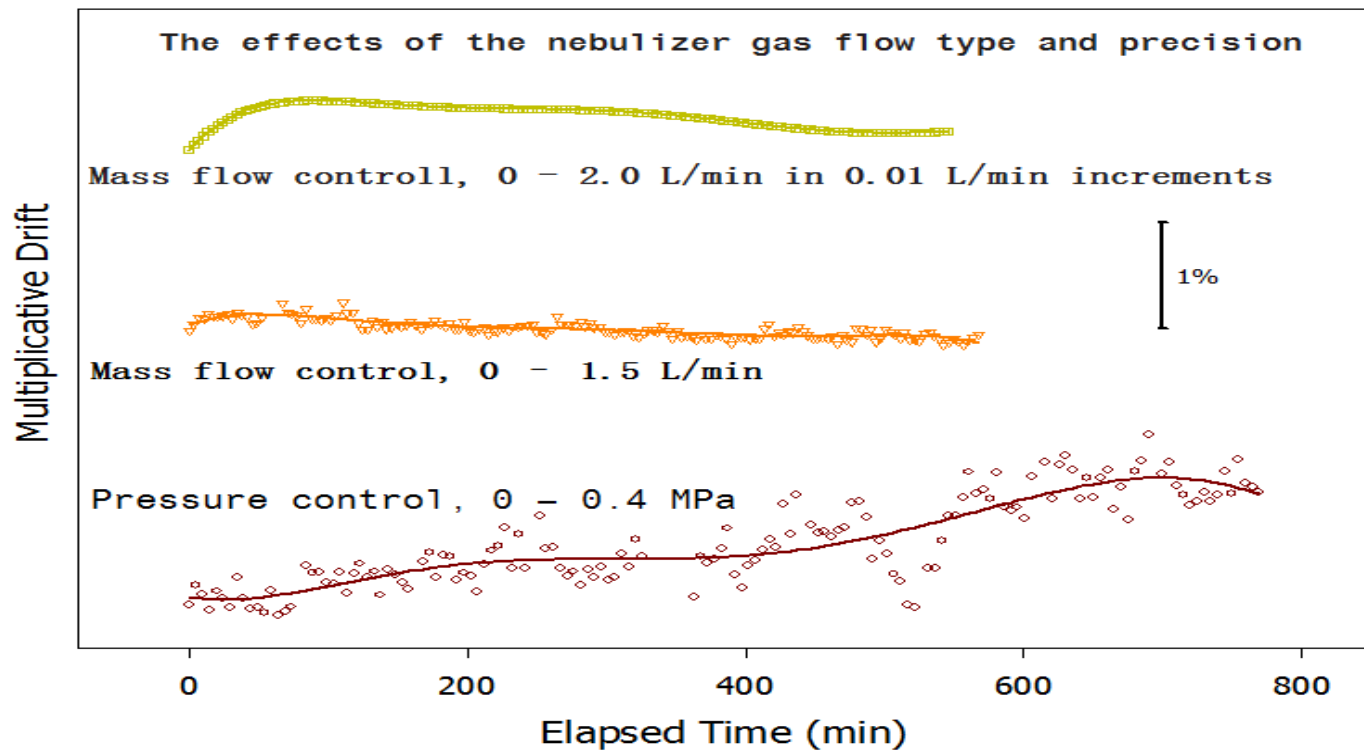
Results: Stability

- Monitor internal standards to check for instrument drift
 - Sc in radial mode, Y in axial mode



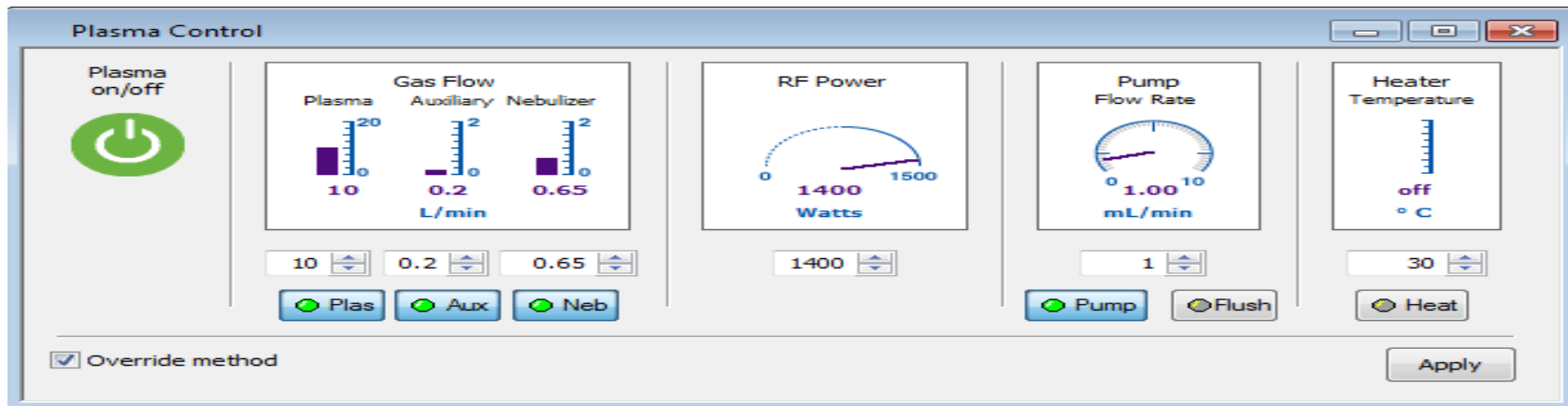
Variations of 5% over 10 hours

如何从0.5% → 0.1% ?



噪音来自蠕动泵、雾化气、电压波动、温度波动... 降低噪音的办法?

噪音来源	处理办法	效果
气体压力波动	使用质量流量计控制雾化器气、冷却气、辅助气流量	有显著效果
电压波动	使用稳压电压	效果不明显
温度变化	配置空调，提高光室恒温精度	有效果

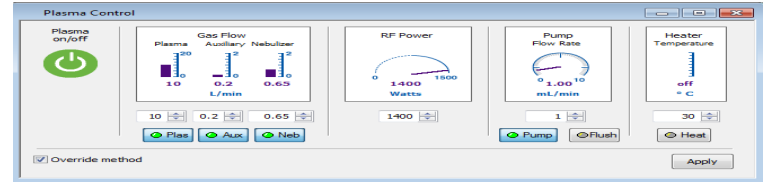


噪音来自蠕动泵、雾化气、电压波动、温度波动。。。

Make a simple Argon diagnostic method and monitor the RSD.

Run a 2v/v% nitric acid solution with four different conditions:

1. Pump on and nebulizer on
2. Pump on and nebulizer off
3. Pump off and nebulizer on
4. Pump off and nebulizer off



A	B	C	D	E	F	G	H	I
Exp_5 Ar-diagnose test								
Plasma power:	1350		Nebulizer type:	CF	resolution	normal		
Nebulizer flow:	0.85		Nebulizer tubing:	B/B	profiling	no		
Auxiliary flow:	0.2		Injector diameter:	2.0 mm	Replicates	10		
Plasma flow:	15		Peak Algorithm:	Area				
Pump speed:	1.5		Points per peak:	3	torch position	-3		
methode:	Exp_5		Results file:	Exp_5				
Read parameters	min 1	max 5						
test	Ar 420.069 % RSD							
pump on neb on	0.28							
pump on neb uit	0.18							
pump off neb on	0.14							
pump off neb out	0.03							

消除噪音，改进RSD到0.1%的关键是消除蠕动泵脉动

- 同步内标校正

Sequence No.: 1
Sample ID: Sample002
Analyst:
Logged In Analyst (Original) : lenovo
Initial Sample Wt:
Dilution: 1144X
Wash Time (before sample):

Autosampler Location:
Date Collected: 2017/10/18 16:47:10
Data Type: Reprocessed on 2017/10/19 14:03:11

Initial Sample Vol:
Sample Prep Vol:

分别使用Y和Sc作为Co和Mn的内标

Mean Data: Sample002

Analyte	Mean Corrected Intensity	Calib. Conc. Units	Std.Dev.	Sample Conc. Units	Std.Dev.	RSD
Sc 357.253	362735.4				1750.31	0.48%
Y 324.227	201340.0				1088.82	0.54%
Y 360.073	260931.3				1393.02	0.53%
Sc 357.634	178463.4				908.55	0.51%
Co 228.616†	5569.9	16.17 mg/L	0.011	18500 mg/L	12.59	0.07%
Co 238.892†	31495.3	15.99 mg/L	0.011	18300 mg/L	12.19	0.07%
Co 236.380†	11857.8	16.08 mg/L	0.008	18400 mg/L	8.90	0.05%
Mn 257.610†	130261.2	23.89 mg/L	0.010	27330 mg/L	11.81	0.04%
Mn 259.372†	270620.9	23.76 mg/L	0.016	27180 mg/L	18.03	0.07%
Mn 260.568†	98557.7	23.73 mg/L	0.019	27140 mg/L	22.25	0.08%

实时内标校正保证
RSD < 0.1%

同步内标校正关键是分析线与内标线有完全相同的曝光时间

Results

Sequence No.: 1

Sample ID: Stand High

Analyst:

Logged In Analyst (Original) : ICP1

Initial Sample Wt: 1 g

Dilution:

Wash Time:

Autosampler Location:

Date Collected: 12/18/2014 10:08:54 AM


Data Type: Reprocessed on 12/30/2014 2:41:03 PM

Initial Sample Vol:

Sample Prep Vol: 100 mL

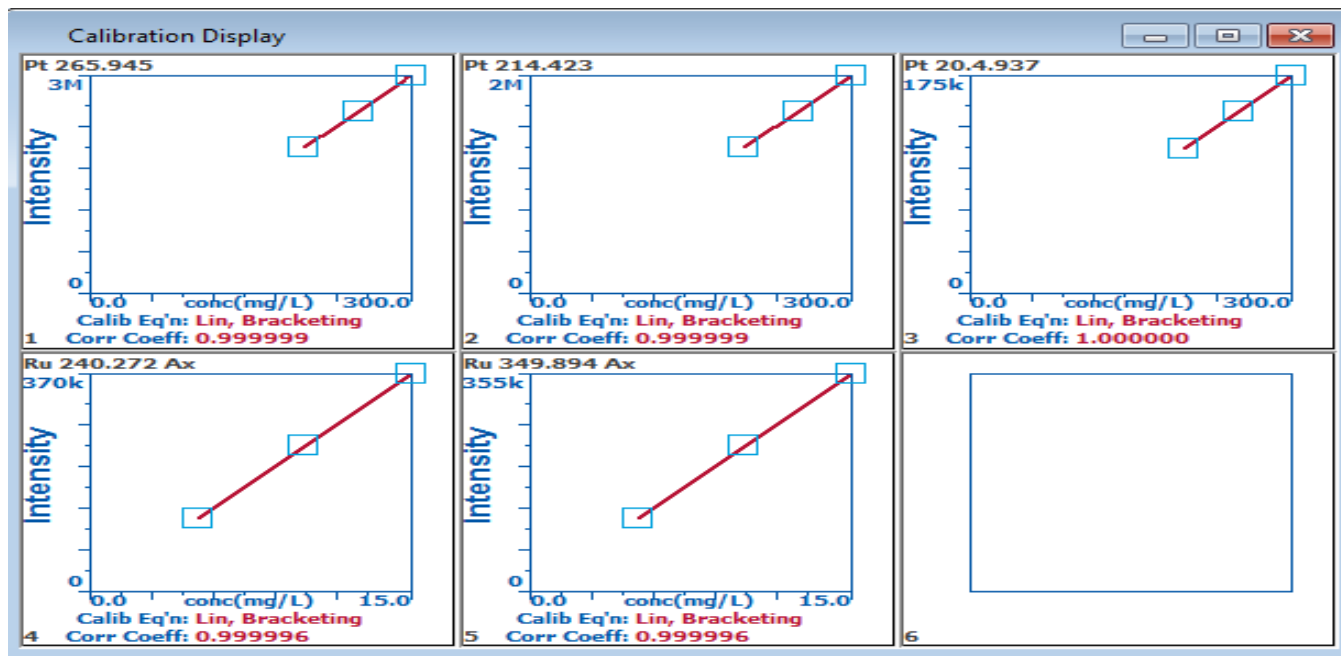
Auto-Integration Report

Analyte	Integration Time (s)	Number of Integrations	Read Time (s)
Be 313.042 Ax	0.010	1000	10.000
Be 313.042 Rad	0.100	100	10.000
Be 313.107 Ax	0.010	1000	10.000
Be 313.107 Rad	0.100	100	10.000
Sc 361.383 Ax	0.010	1000	10.000
Sc 361.383 Rad	0.500	20	10.000
Y 371.029 Ax	0.010	1000	10.000
Y 371.029 Rad	0.500	20	10.000
Yb 289.138 Ax	0.100	100	10.000
Yb 289.138 Rad	0.500	20	10.000
Pt 193.700 Rad	0.500	20	10.000
Pt 204.937 Rad	0.500	20	10.000
Pt 214.423 Rad	0.500	20	10.000
Pt 265.945 Ax	0.010	1000	10.000
Pt 265.945 Rad	0.100	100	10.000
Ru 240.272 Ax	0.100	100	10.000
Ru 279.535 Ax	0.100	100	10.000
Ru 349.894 Ax	0.100	100	10.000



高性能ICPOES应用实例一：贵金属检测

Linear Bracketing拟合保证样品、标准的分析线与内标同步曝光



Full Compliance with ISO11494, 11495, etc.

高性能ICPOES应用实例一：贵金属检测

Pt、Ru检测结果RSD%<0.1%

Sequence No.: 3
Sample ID: Std2
Analyst:
Logged In Analyst (Original) : ICP1
Initial Sample Wt:
Dilution:
Wash Time:

Autosampler Location: 3
Date Collected: 12/18/2014 2:02:20 PM
Data Type: Reprocessed on 12/30/2014 3:08:56 PM

Initial Sample Vol:
Sample Prep Vol:

Mean Data: Std2

Analyte	Mean Corrected Intensity	Std.Dev.	RSD	Conc.	Calib Units
Be 313.107 Ax	2119890.3	7221.66	0.34%	98.67	%
Be 313.042 Ax	4285765.2	14410.54	0.34%	98.72	%
Y 371.029 Ax	1337847.3	3817.57	0.29%	98.38	%
Yb 289.138 Ax	154247.0	448.19	0.29%	98.23	%
Sc 361.383 Ax	1485809.9	4170.77	0.28%	98.30	%
Pt 265.945†	2529182.3	818.69	0.03%	[250]	mg/L
Pt 214.423†	1699057.0	632.78	0.04%	[250]	mg/L
Pt 20.4.937†	145684.1	63.67	0.04%	[250]	mg/L
Ru 240.272 Axt	247572.0	177.19	0.07%	[10]	mg/L
Ru 349.894 Axt	236982.8	20.39	0.01%	[10]	mg/L

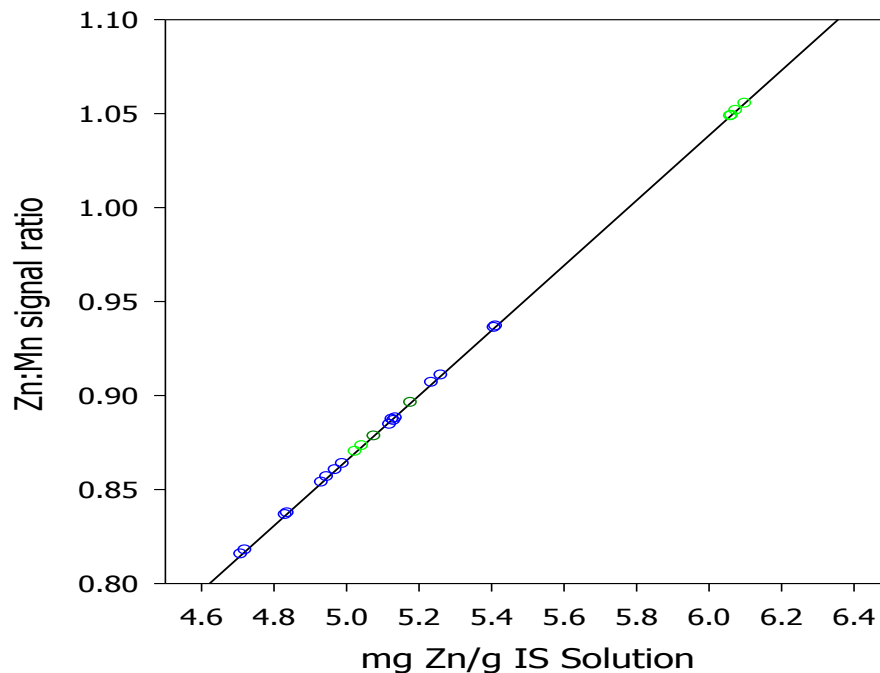
内标

分析物

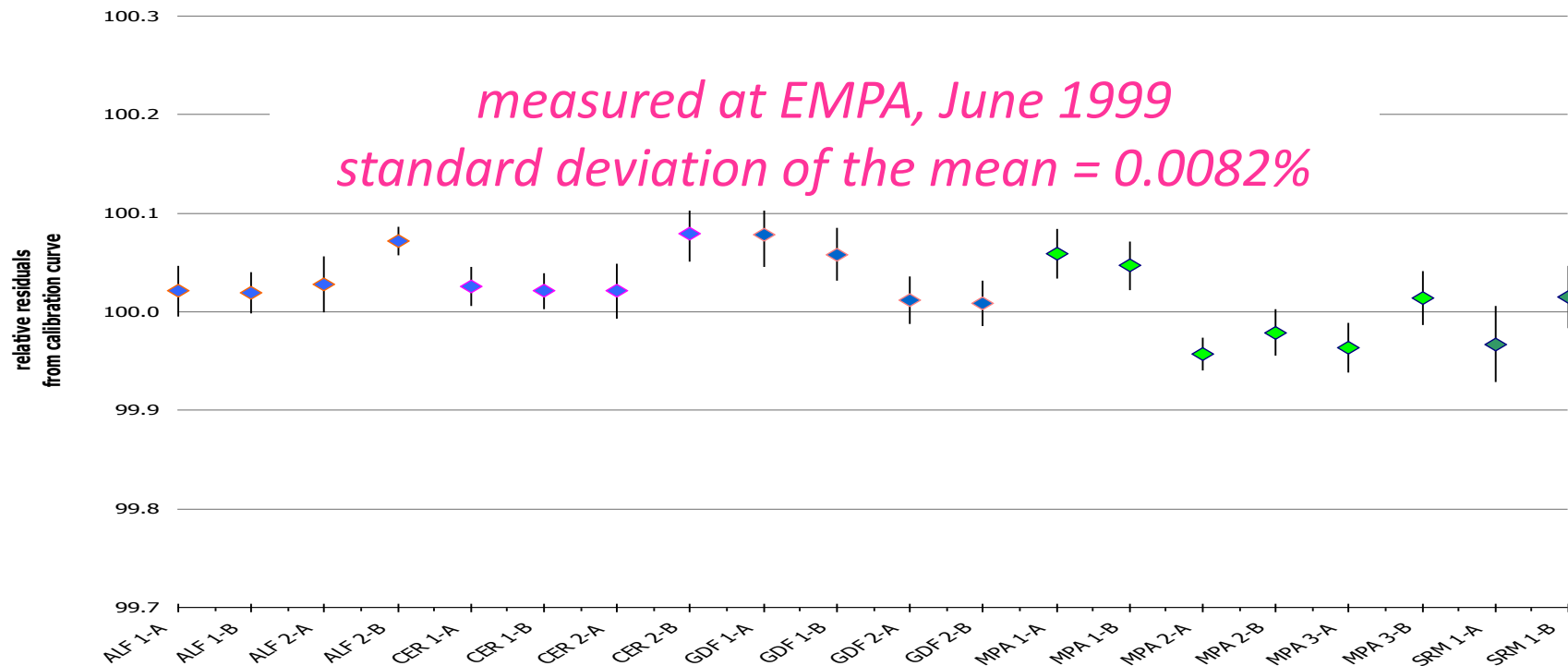
高性能ICPOES应用实例二：高纯金属锌分析

US — Swiss Zn Comparison

- comparison of NIST SRM against...
 - EMPA distilled Zn
 - high purity metals
- calibration curve for 20 solutions
 - 800 min expt
 - 0.0082% solution-to-solution variability



高性能ICPOES应用实例二：高纯金属锌分析



高性能ICPOES应用实例三：NdFeB合金主量元素分析

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ICP-AES 法高精度测定钕铁硼合金中主量元素

徐 静*，李明来，李世鹏，彭海军，赵 斌，于敦波

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Table 7 Precisions ($n = 10$) and recoveries of the method

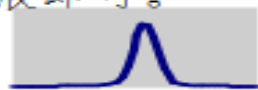
Component	Found $w / (\%, \text{ mass fraction})$	Average $w / (\%, \text{ mass fraction})$	RSD/ %	Added $w / (\%, \text{ mass fraction})$	Found $w / (\%, \text{ mass fraction})$	Recovery/ %
Nd	29.90, 29.88, 29.84, 29.90, 29.87, 29.88, 29.85, 29.86, 29.81, 29.85	29.86	0.09	30.0	58.1	97
Fe	69.05, 69.07, 69.11, 69.05, 69.08, 69.07, 69.10, 69.09, 69.14, 69.09	69.08	0.04	70.0	142.95	103
B	1.051, 1.050, 1.045, 1.050, 1.051, 1.047, 1.053, 1.046, 1.053, 1.055	1.050	0.31	1.0	2.01	98

高性能ICPOES其他要求：复杂样品分析能力

复杂样品光谱干扰消除之谱图解析技术MSF

- ▶ PerkinElmer 独有的扣除光谱干扰功能，解决了 ICP-OES分析复杂基体样品中的谱线干扰问题，其原理是利用现代化学计量学和多元线性回归算法，在分析复杂基体样品时，通过数学模型将分析谱线从干扰光谱中剥离出来。只需要保持峰型稳定，所以该模型通常与样品浓度及特定的离子状况等无关，

因此实际应用非常方便，只需要空白溶液、待测元素溶液及干扰元素溶液即可。



Analyte
纯分析元素



Blank
空白



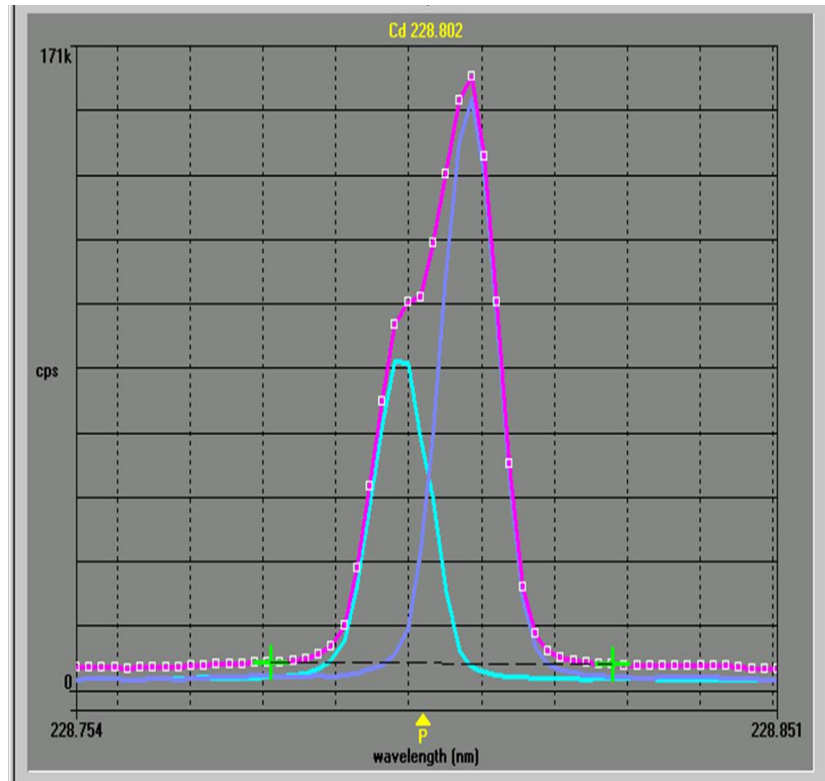
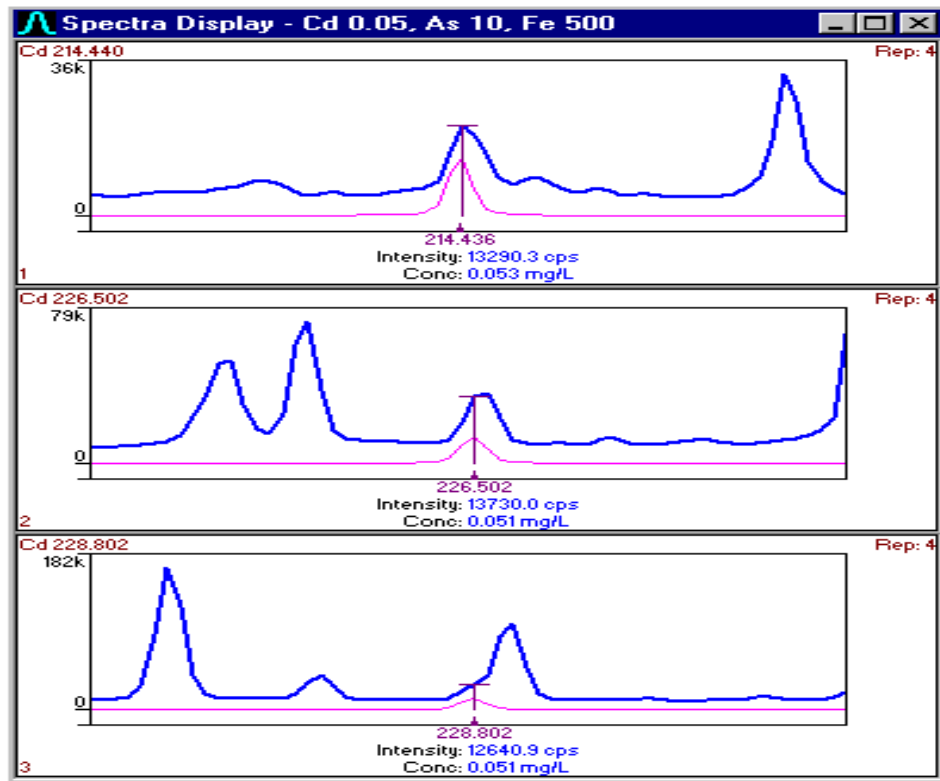
Matrix
纯基体

=

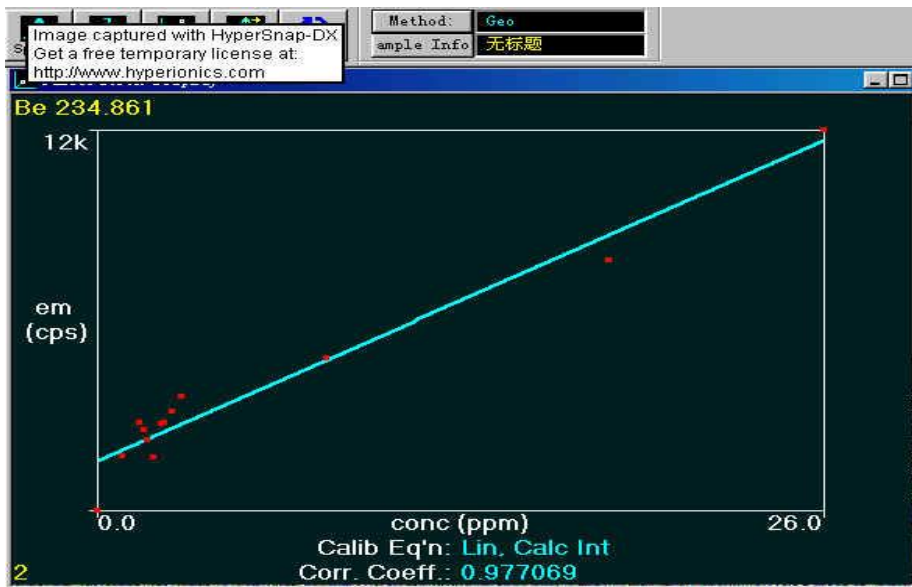


Measured Spectrum
实际测定的光谱图

MSF模型解析之土壤中Cd（干扰物为Fe和As）



MSF模型解析用于Be的测定(干扰Co、Mo、Fe、Cu)



没有使用MSF解析的拟合曲线

$r=0.977$



使用MSF解析后的拟合曲线

$r>0.999$

高性能ICPOES其他要求：复杂样品分析能力 复杂样品得到理想检测结果

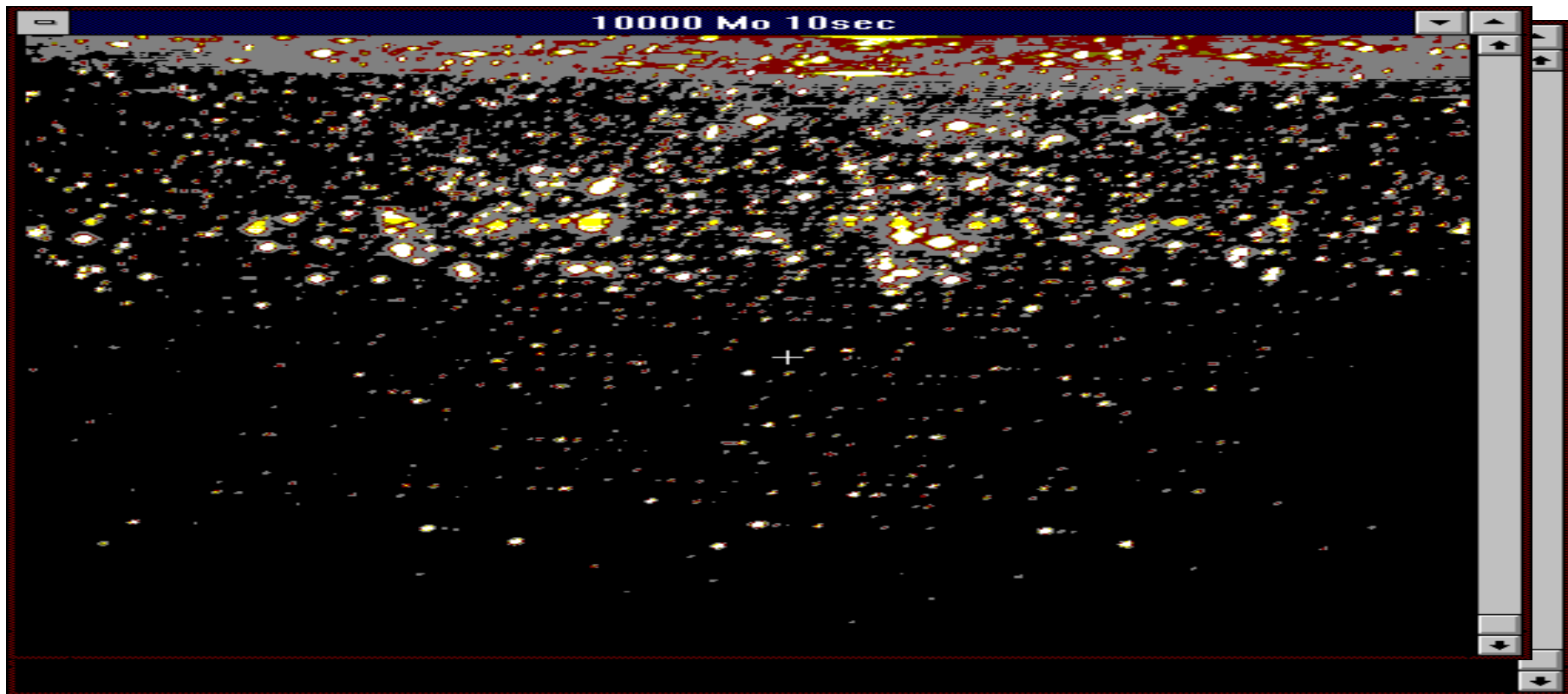
Stainless Steel Type 304L B.S. 81G Values expressed as weight%

Element and Wavelength	Reference Value	Avio500 Value
B 249.772	0.0005 ±0.001	0.00049 ±0.000005
Co 228.616	0.29 ±0.01	0.296 ±0.003
Cr 283.563	18.65 ±0.08	18.73 ±0.075
Cu 324.752	0.54 ±0.02	0.543 ±0.004
Mn 294.920	1.69 ±0.03	1.72 ±0.013
Mo 203.845	0.69 ±0.02	0.685 ±0.006

双向观测的ICP-OES，才可以同时分析出百分含量的主成分和固体中ppm量级的痕量成分。

高性能ICPOES其他要求：得到完整光谱学信息并解决干扰问题

实际样品的光谱图和光谱干扰



中阶梯光栅与跨级干扰 (1)

- 中阶梯光栅虽然有非常好的光学分辨能力，但由于使用大级数分光，需要注意光谱级次间的干扰，如：
- Pb220.353nm，本来不会受到Cu的干扰，最近的Cu谱线波长也会相差0.3nm。

Search parameters

Center wavelength nm Wavelength range (+/-) nm

Wavelengths All Recommended

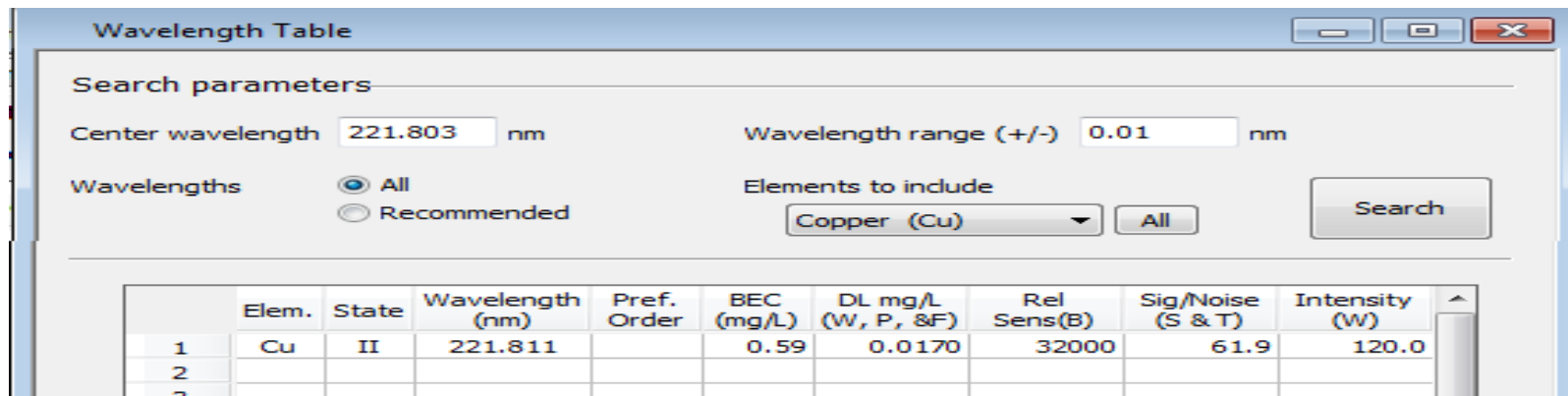
Elements to include

	Elem.	State	Wavelength (nm)	Pref. Order	BEC (mg/L)	DL mg/L (W, P, &F)	Rel Sens(B)	Sig/Noise (S & T)	Intensity (W)
1	Cu	I	219.959		0.32	0.0097	45000	41.6	160.0
2	Cu	I	219.976					23.3	
3	Cu	I	220.050						
4	Cu	II	220.057						

- 但某型号仪器使用的光学级次为153级，会受到152级次上的Cu谱线的严重干扰。

中阶梯光栅与跨级干扰 (2)

- 接上页:
- Pb220.353nm (153级) 在152级对应的波长为:
- 221.803nm ($220.353\text{nm} \times 153/152$), 与221.811nm的Cu线相近



The screenshot shows a software window titled "Wavelength Table". It has a search interface with the following parameters:

- Center wavelength: 221.803 nm
- Wavelength range (+/-): 0.01 nm
- Wavelengths: All, Recommended
- Elements to include: Copper (Cu) (selected from a dropdown), All (button)
- Search button

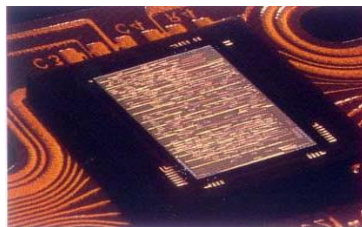
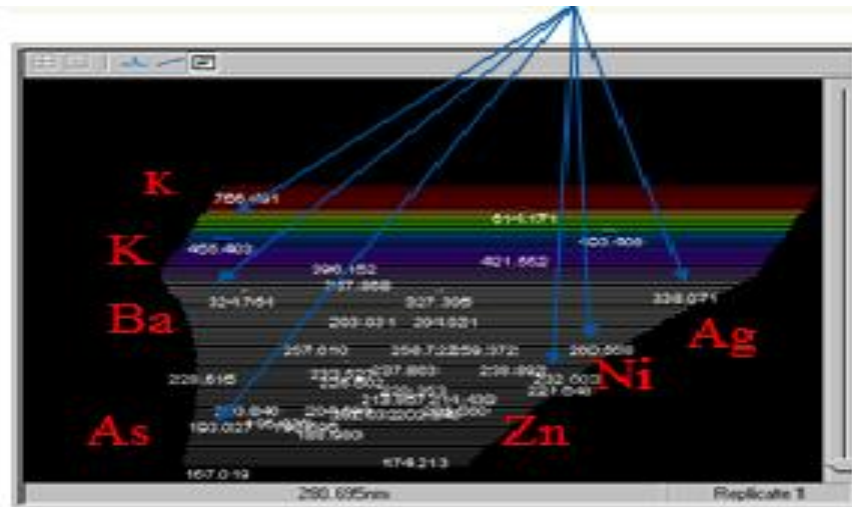
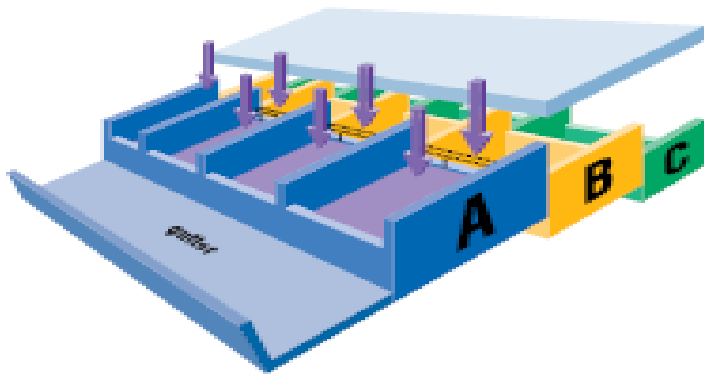
Below the search parameters is a table with the following data:

	Elem.	State	Wavelength (nm)	Pref. Order	BEC (mg/L)	DL mg/L (W, P, &F)	Rel Sens(B)	Sig/Noise (S & T)	Intensity (W)
1	Cu	II	221.811		0.59	0.0170	32000	61.9	120.0
2									
3									

- 221.811nm (152级) 相当于220.361nm (153), 将对Pb220.353nm (153) 产生严重的干扰, 使含铜(如青铜) 样品中Pb的测定出现大问题!

高性能ICPOES其他要求：复杂样品分析能力 需要处理跨光谱级次的干扰

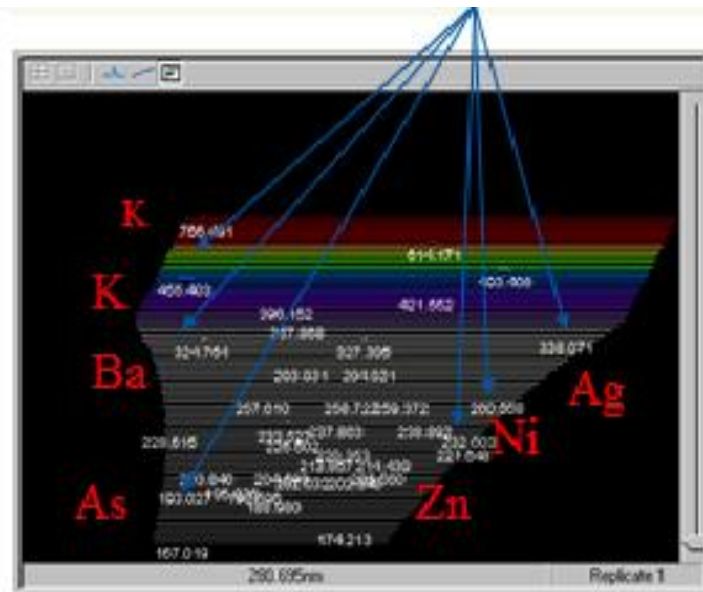
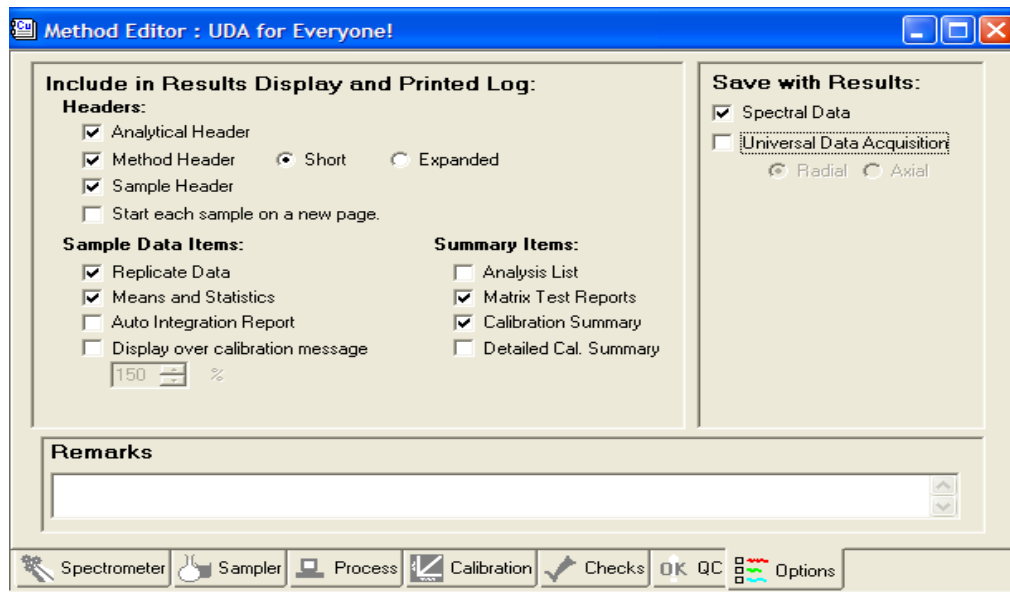
- 1、检测器上的处理。
- 2、光学级次的选择。



高性能ICPOES其他要求：得到完整的光谱学信息

什么是全谱直读？

- 记录全部的光学信息而不是用户选择的几条谱线的信息。



高性能ICPOES其他要求：得到完整的光谱学信息

全谱直读的作用：解决谱线选择错误

- 在检测结果中请注意：
 - Fe的回收率较低
 - Co的结果为负值
 - Sn的结果很高
- 那么！
 - 通常，重做吧！

Analyte	Wavelength (nm)	Count	Line	Calc	Int	Conc.	Units	Std.Dev.
Co	238.892	1	Lin	Calc	Int	0.0	97880	
Fe	238.204	1	Lin	Calc	Int	0.0	157600	
Sn	235.485	1	Lin	Calc	Int	0.0	10660	

Sequence No.:	1	Autosampler:	
Sample ID:	200fe	Date Collecte	
Analyst:		Data Type:	Re
Logged In Analyst (Original):	chiss	Initial Samp	
Initial Sample Wt:		Sample Prep	
Dilution:			

Analyte	Mean Corrected Intensity	Calib. Conc. Units	Std.Dev.
Y 371.029	3182157.5	97.10 %	0.529
Co 238.892+	-3258283.5	-33.29 mg/L	0.255
Fe 238.204	27720743.8	175.9 mg/L	0.67
Sn 235.485+	568162.7	53.31 mg/L	0.007

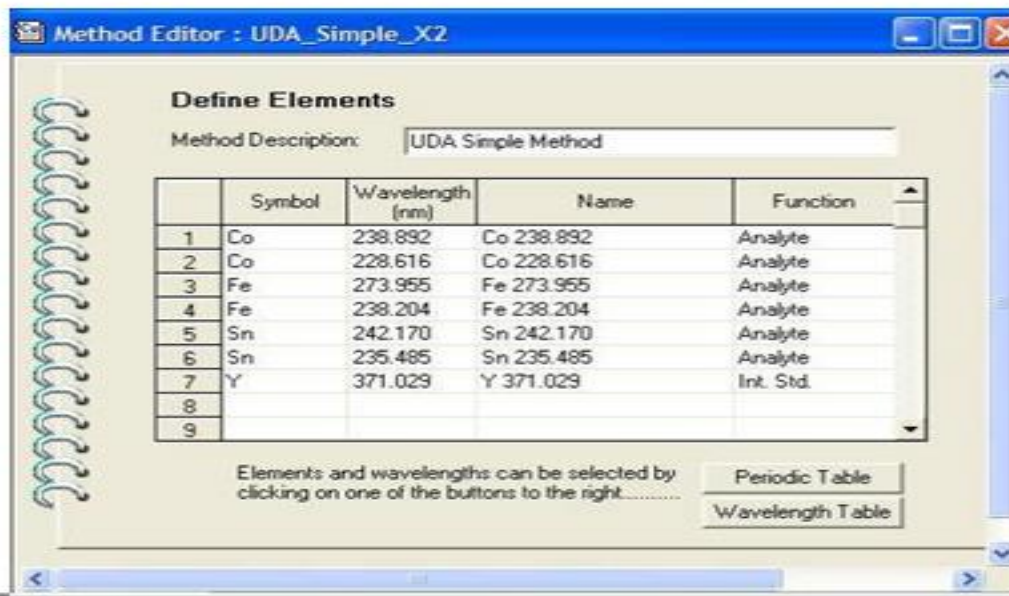
高性能ICPOES其他要求：得到完整的光谱学信息

全谱直读的作用：解决谱线选择错误

- ▶ 对于全谱直读仪器，那么你可以随时随地在检测方法中加入其他谱线并直接再处理数据即可。

添加 Co 228, Fe 273, Sn242

数据再处理



Method Editor : UDA_Simple_X2

Define Elements

Method Description: UDA Simple Method

	Symbol	Wavelength (nm)	Name	Function
1	Co	238.892	Co 238.892	Analyte
2	Co	228.616	Co 228.616	Analyte
3	Fe	273.955	Fe 273.955	Analyte
4	Fe	238.204	Fe 238.204	Analyte
5	Sn	242.170	Sn 242.170	Analyte
6	Sn	235.485	Sn 235.485	Analyte
7	Y	371.029	Y 371.029	Int. Std.
8				
9				

Elements and wavelengths can be selected by clicking on one of the buttons to the right.....

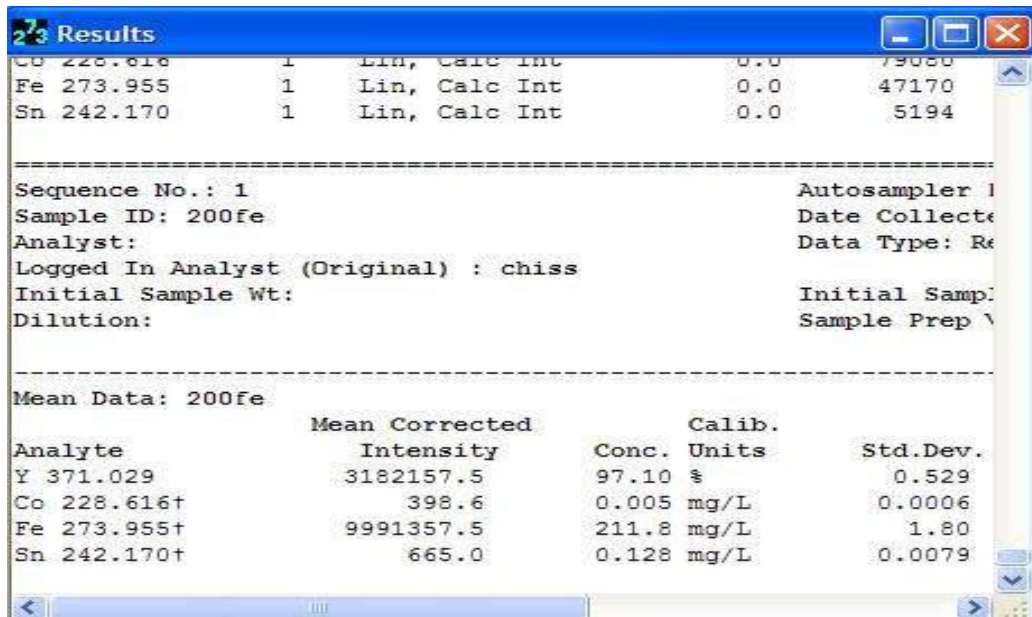
Periodic Table
Wavelength Table



高性能ICPOES其他要求：得到完整的光谱学信息

全谱直读的作用：解决谱线选择错误

- 现在请注意：Fe的结果更加的接近200ppm的真值，同时Co和Sn的结果也已经消除了干扰。
- 可以对任何元素，任何干扰进行处理，不需要重新分析！！！！



23 Results

Element	Conc.	Units
Co 228.616	0.0	79080
Fe 273.955	0.0	47170
Sn 242.170	0.0	5194

Sequence No.: 1
Sample ID: 200fe
Analyst:
Logged In Analyst (Original) : chiss
Initial Sample Wt:
Dilution:

Mean Data: 200fe

Analyte	Mean Corrected Intensity	Calib. Conc. Units	Std.Dev.
Y 371.029	3182157.5	97.10 %	0.529
Co 228.616+	398.6	0.005 mg/L	0.0006
Fe 273.955+	9991357.5	211.8 mg/L	1.80
Sn 242.170+	665.0	0.128 mg/L	0.0079

高性能ICPOES其他要求：得到完整的光谱学信息

全谱直读的作用：增加分析元素与谱线

- UDA 校准溶液包
 - 共4瓶各100ml的溶液
 - 10 ppm
 - 稀释1:10
 - 1 ppm
 - 元素周期表中所有元素

PerkinElmer UDA Standards Kit Part no. N9300685



高性能ICPOES的要求：得到完整光谱学，不能缺少重要谱线 检测器与光学系统的匹配问题

- 某仪器：
- 光栅刻线52.91条/mm，闪耀角63.5°。光学系统焦距为383mm。
- 检测器参数：像素大于290000（540*540），像素宽度0.028mm（15mm/540）
- Order 82时：
中心波长 $\lambda=2*(1/52.91)*\sin63.5^\circ *1000000/82=2*0.0189*0.895*1000000/82=412.57\text{nm}$
- Order 83时：
中心波长 $\lambda=2*(1/52.91)*\sin63.5^\circ *1000000/83=2*0.0189*0.895*1000000/83=407.6\text{nm}$
- Order 84时：
中心波长 $\lambda=2*(1/52.91)*\sin63.5^\circ *1000000/84=2*0.0189*0.895*1000000/84=402.75\text{nm}$
- 所以当光学级数为83时，检测器需要覆盖的波长为 $(412.57-402.75)/2=4.91\text{nm}$
- 根据光栅方程计算：
中心波长 $\lambda=2*(1/52.91)*\sin63.5^\circ *1000000/83=2*0.0189*0.895*1000000/83=407.6\text{nm}$
- 光栅角色散率 $=m/(d*\cos\beta)=83/(0.0189*0.446)=9846.49.85\text{弧度/mm}=0.0098\text{弧度/nm}$
- 光学系统线色散率倒数 $=1/(\text{角色散率*焦距})=1/(0.0098*383)=0.2652\text{nm/mm}$
- 检测器像素分辨率 $=\text{线色散率倒数*像素宽度}=0.2652*0.028=0.0074\text{nm}$
- 检测器每行覆盖波长 $=\text{每个像素覆盖波长*每行像素数}=0.0074*540=4.01\text{nm}$
- **严重后果：该仪器没有La408.672nm和La398.852!**

The screenshot shows the 'Map Editor - For Element La' window. It contains a table with the following data:

Wavelength & Order	Wavelength Range	Column	Row	Peak Status	State	Relative Intensity	Available for Analysis	Auto Select for New Method
333.749 (101)	High	280.94	148.14	Not Located		1500000	<input checked="" type="checkbox"/>	<input type="checkbox"/>
379.478 (089)	High	375.15	113.55	Not Located		1200000	<input checked="" type="checkbox"/>	<input type="checkbox"/>
408.672 (082)	High	2.80	95.18	Not Located		1800000	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
412.323 (082)	High	429.22	96.09	Not Located		1500000	<input checked="" type="checkbox"/>	<input type="checkbox"/>
419.665 (080)	High	88.50	90.35	Not Located		500000	<input checked="" type="checkbox"/>	<input type="checkbox"/>

Below the table, there are tabs for 'Peak Location', 'Subarray', and 'General'. A message at the bottom says 'Indicates that we recommend you to use this new line.' There are 'Add Lines...' and 'Delete...' buttons.

An error dialog box is overlaid on the bottom right, with a red border around the message: 'Wavelength 398.852 is not available for this instrument. You are not able to add this line to the Map database.' The dialog has an 'OK' button.